JC17 Rec'd F PTO 15 JUN 2005

## **INFORMATION DISCLOSURE STATEMENT TRANSMITTAL**

To Commissioner For Patents

Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.

9011110041					
Application Number	iU/539251				
Filing Date					
First Named Inventor	Martijn LANKHORST				
Group Art Unit					
Examiner Name					
Atty. Docket Number	NL03 0259 US				

Examiner Initials*	Cite No.1	Document Number -NoKind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear			
a		us- US 5 714 768	02-03-1998	WICKER GUY C ET AL				
Or		us- 2004/001374	01-01-2004	NORITA KIYOYUKI ET AL				
FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No.	Document Number (ctry³-no.⁴-kind⁵, if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	᠇ᢦ		
er		EP 1 343 154	09-10-2003	MICHIKAZU, HORIE ET AL .				
01		EP 0 495 494	07-22-1992	OVSHINSKY, STANFORD ET AL				
a		EP 1 202 285	05-02-2002	NISHIHARA, TAKASHI ET AL				
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NON-PATENT/LITERATURE/DOCUMENTS								
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**U.S. PATENT DOCUMENTS** 

1	BORG H J ET AL: "PHASE-CHANGE MEDIA FOR HIGH-NUMERICAL-APERTURE AND BLUE- WAVELENGTH RECORDING" JAPANESE JOURNAL OF APPL. PHYSIGS, MARCH 2001, VOL. 40, PP1592-1597
	NJOROGE W K ET AL: "CRYSTALLIZATION KINETICS OF SPUTTER-DEPOSITED AMORPHOUS AGINSBTE FILMS" JOURNAL OF APPL. PHYSICS, 15 OCT. 2001
	GUO-FU ZHOU ET AL: "HIGH PERFORMANCE MEDIA FOR PHASE CHANGE OPTICAL RECORDING" JAPANESE JOURNAL OF APPLIED PHYSICS, VOL. 38, PAGES 1625-1628, PART 1-NO. 3B, MARCH 1999

Examiner Signature	90 10	Date Considered	11/28/	07
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not obtation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\*Unique citation designation number. \*See stracted Kinds of U.S. Patent Documents. \*Enter Office that issued the document, by the two-latter code (WPO Standard ST.3). \*For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. \*Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. \*Applicant is to place a check mark here if English language translation is attached.